



Texas Instruments

PMP4390 Test Procedure

China Power Reference Design

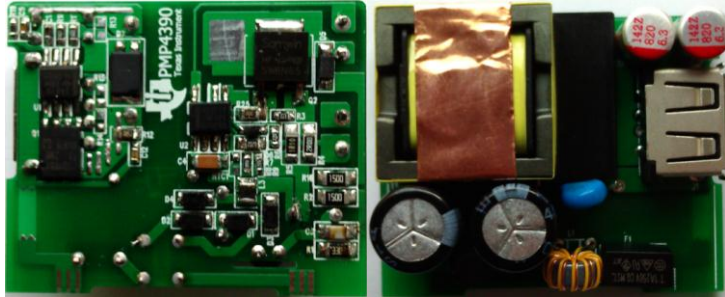
REV A

12/09/2013

1 GENERAL

1.1 PURPOSE

To provide detailed data for evaluating and verifying the PMP4390, which uses TI new Primary Side Controller UCC28713 and synchronous rectified controller UCC24610 for 5.5V3A adapter with small form factor: 44mmx35mmx15mm. The below photo shows this demo board.



1.2 REFERENCE DOCUMENTATION

Schematic PMP4390_SCH.PDF

Assembly PMP4390_PCB.PDF

BOM

Gerber files

Promotion tools

1.3 TEST EQUIPMENTS

Power-meter: YOKOGAWA WT210

Multi-meter(current): Fluke 8845A

Multi-meter(voltage): Fluke 187

AC Source: Chroma 61530

Electronic load: Chroma 63105A module

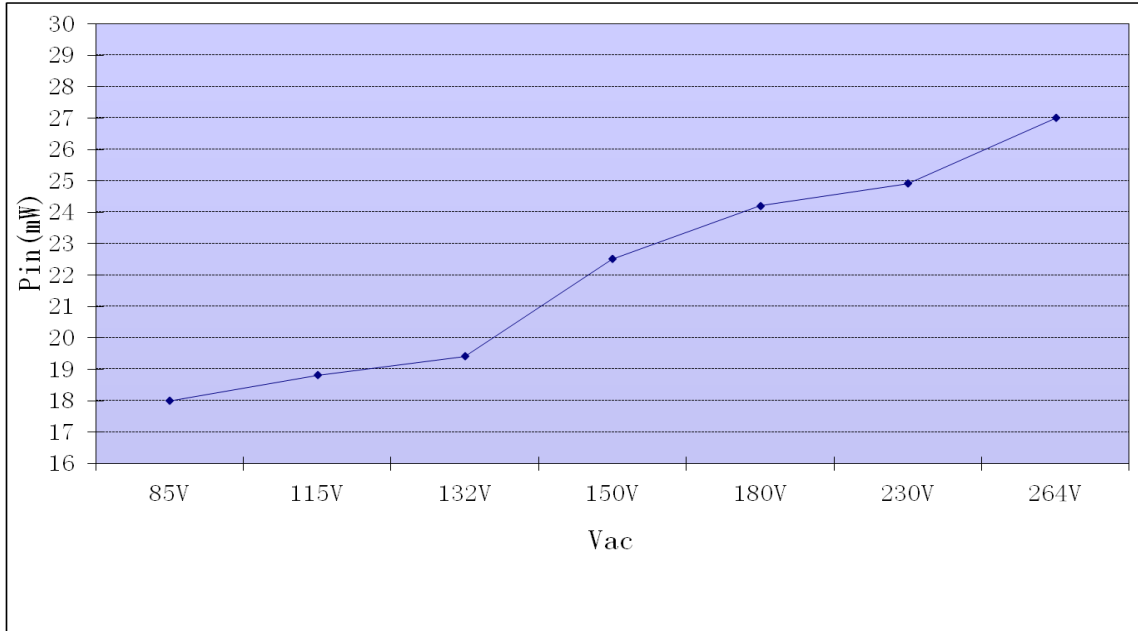
Testing demoboard

2 INPUT CHARACTERISTICS

Efficiency is tested on USB-end

**Otherwise Specified, the test is under the condition with
100cm cable**

2.1 STANDBY POWER



2.2 EFFICIENCY DATA

Notes: efficiency test is based on USB port

85v			
Pi (w)	Io (A)	Vo (V)	efficiency
1.025	0.15	5.197	0.761
1.902	0.3	5.206	0.821
2.339	0.375	5.211	0.835
4.604	0.75	5.246	0.855
6.9	1.125	5.276	0.86
9.28	1.5	5.311	0.858
11.74	1.875	5.35	0.854
14.25	2.25	5.402	0.853
16.81	2.625	5.442	0.85
19.35	3	5.476	0.849
132v			
Pi (w)	Io (A)	Vo (V)	efficiency
1.052	0.15	5.2	0.741
1.946	0.3	5.202	0.802
2.378	0.375	5.21	0.822
4.602	0.75	5.244	0.855
6.87	1.125	5.281	0.865
9.2	1.5	5.312	0.866
11.58	1.875	5.347	0.866

115v			
Pi (w)	Io (A)	Vo (V)	efficiency
1.038	0.15	5.195	0.751
1.925	0.3	5.203	0.811
2.361	0.375	5.209	0.827
4.598	0.75	5.243	0.855
6.882	1.125	5.279	0.863
9.219	1.5	5.31	0.864
11.62	1.875	5.353	0.864
14.05	2.25	5.394	0.864
16.53	2.625	5.436	0.863
18.99	3	5.461	0.863
150v			
Pi (w)	Io (A)	Vo (V)	efficiency
1.085	0.15	5.205	0.72
1.976	0.3	5.203	0.79
2.406	0.375	5.209	0.812
4.627	0.75	5.242	0.85
6.899	1.125	5.279	0.861
9.213	1.5	5.312	0.865
11.58	1.875	5.346	0.866

14	2.25	5.394	0.867
16.44	2.625	5.438	0.868
18.86	3	5.463	0.869

180v

Pi (w)	Io(A)	Vo(V)	efficiency
1.133	0.15	5.203	0.689
2.026	0.3	5.202	0.77
2.455	0.375	5.209	0.796
4.665	0.75	5.242	0.843
6.916	1.125	5.28	0.859
9.25	1.5	5.315	0.862
11.62	1.875	5.348	0.863
13.99	2.25	5.395	0.868
16.46	2.625	5.434	0.867
18.93	3	5.467	0.866

230v

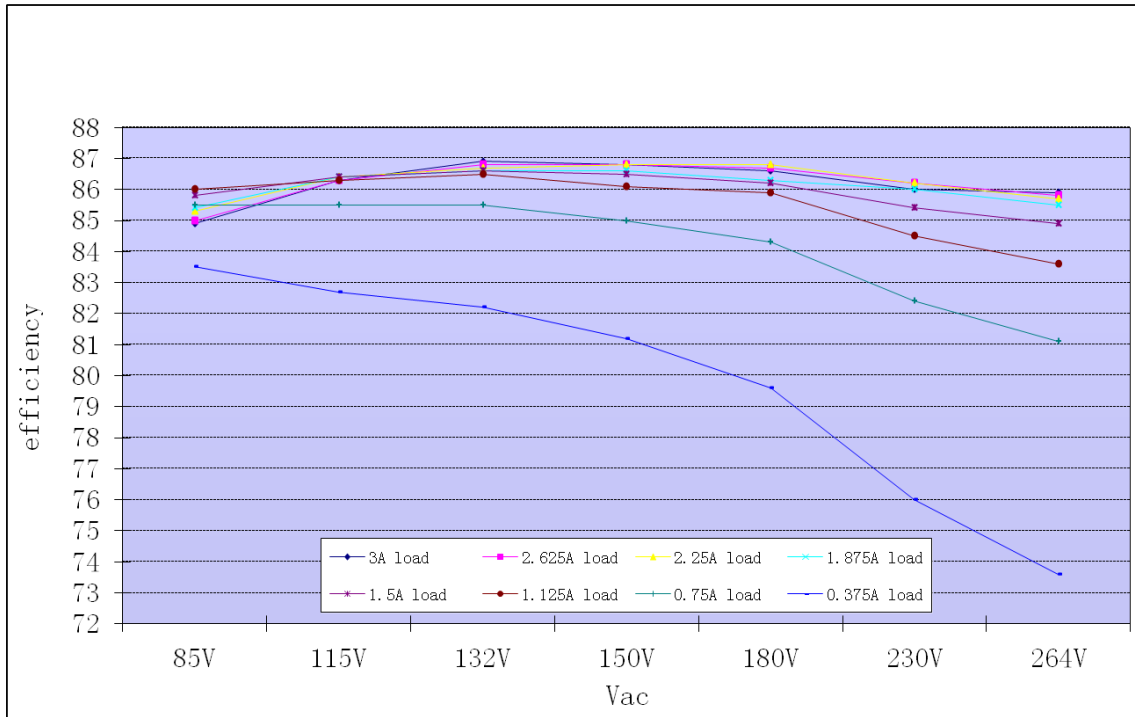
Pi (w)	Io(A)	Vo(V)	efficiency
1.27	0.15	5.193	0.613
2.14	0.3	5.2	0.729
2.57	0.375	5.206	0.76
4.766	0.75	5.236	0.824
7.027	1.125	5.275	0.845
9.328	1.5	5.312	0.854
11.66	1.875	5.348	0.86
14.05	2.25	5.383	0.862
16.54	2.625	5.433	0.862
19	3	5.448	0.86

13.99	2.25	5.394	0.868
16.43	2.625	5.434	0.868
18.88	3	5.465	0.868

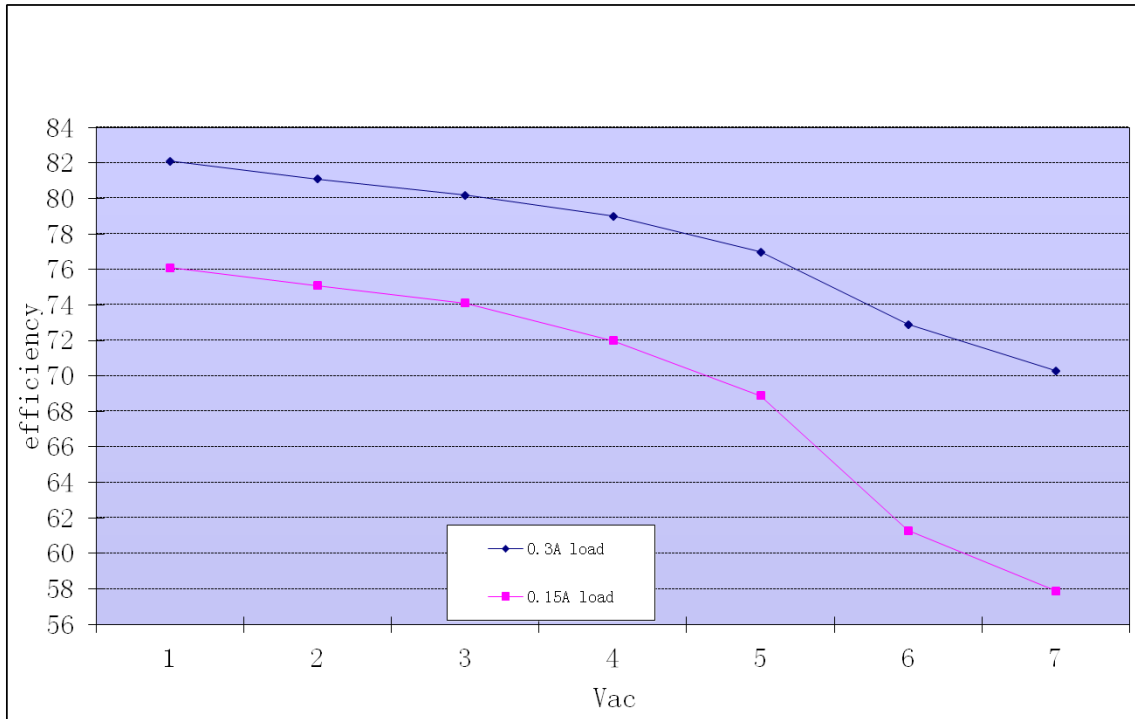
264v

Pi (w)	Io(A)	Vo(V)	efficiency
1.345	0.15	5.192	0.579
2.219	0.3	5.2	0.703
2.654	0.375	5.207	0.736
4.846	0.75	5.237	0.811
7.099	1.125	5.274	0.836
9.388	1.5	5.312	0.849
11.73	1.875	5.348	0.855
14.14	2.25	5.383	0.857
16.62	2.625	5.432	0.858
19.1	3	5.469	0.859

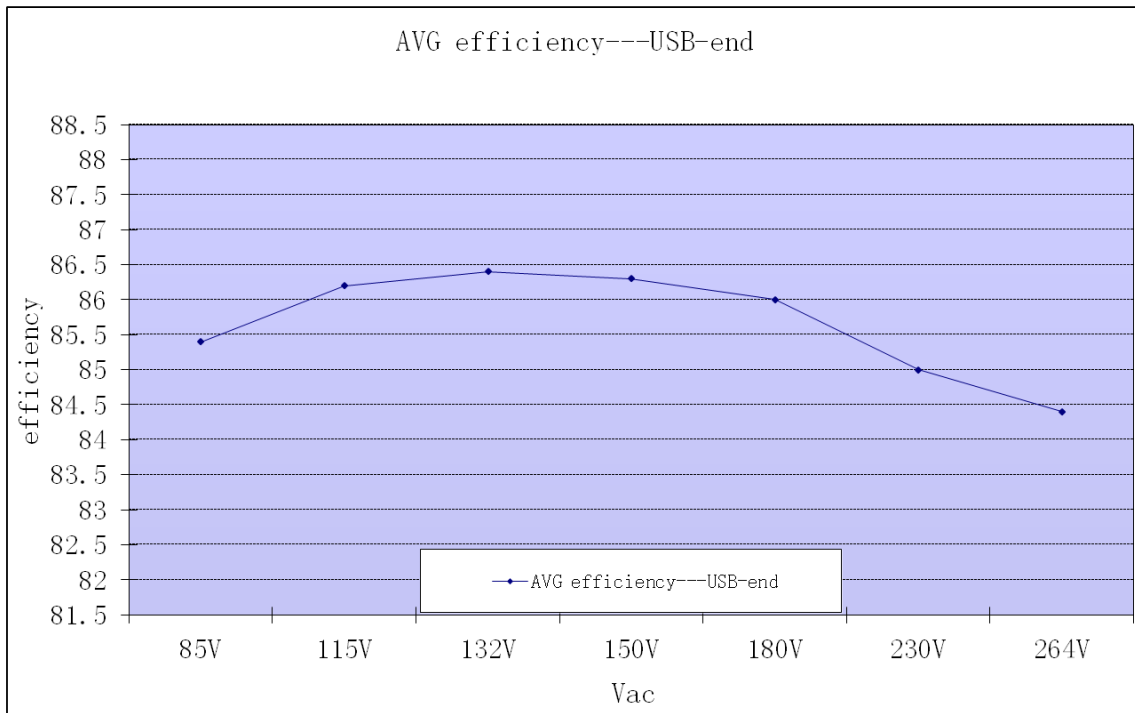
2.2.1 Load and input voltage Vs efficiency curve tested at USB-end



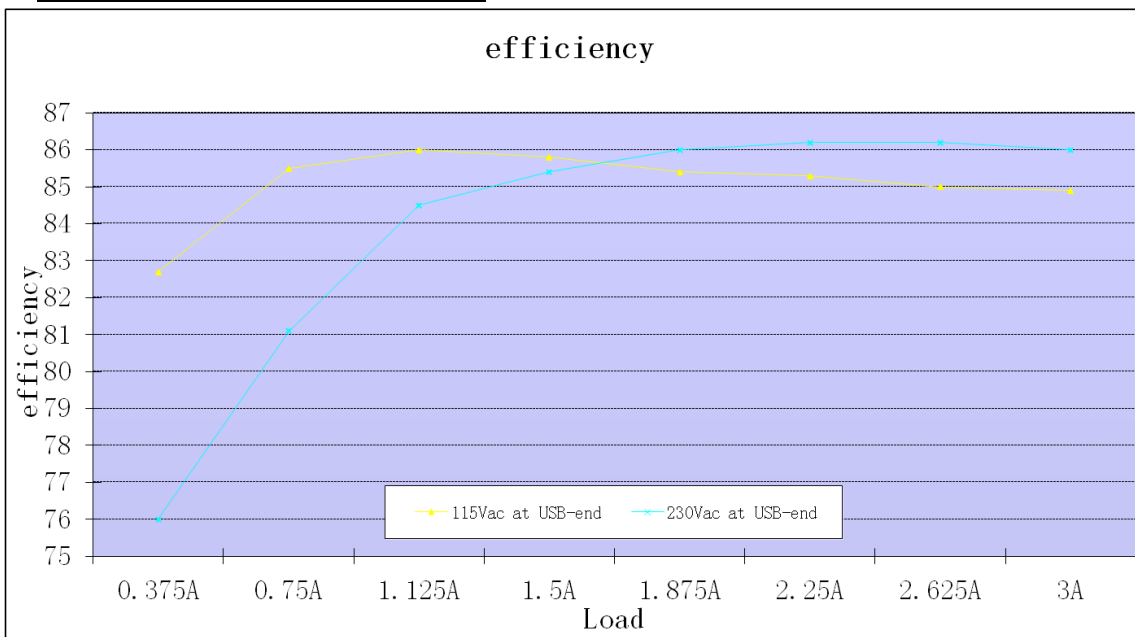
2.2.2 efficiency curve at 5% and 10% of full load



2.2.3 Average efficiency curve at 0.75A,1.5A,2.25A,3A



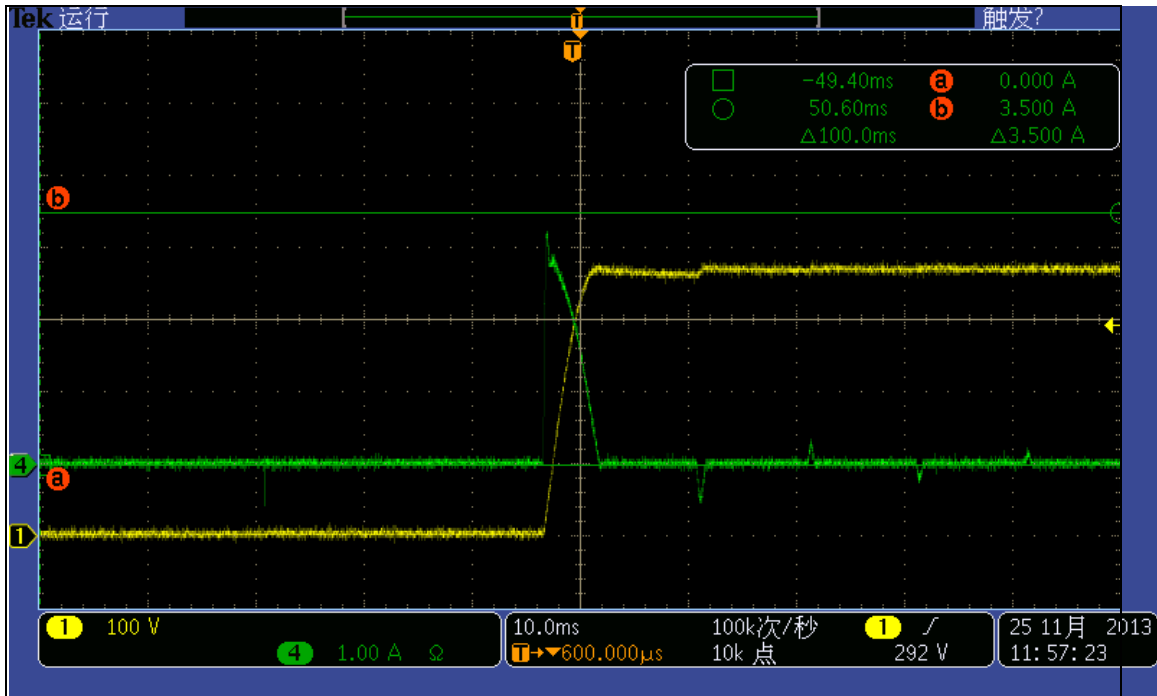
2.2.5 Efficiency Vs load curve



2.3 INPUT CURRENT

Vin(Vac)	Freq(Hz)	Iin(Arms)	Pass/Fail
85	60	0.36	

2.4 INPUT INRUSH CURRENT

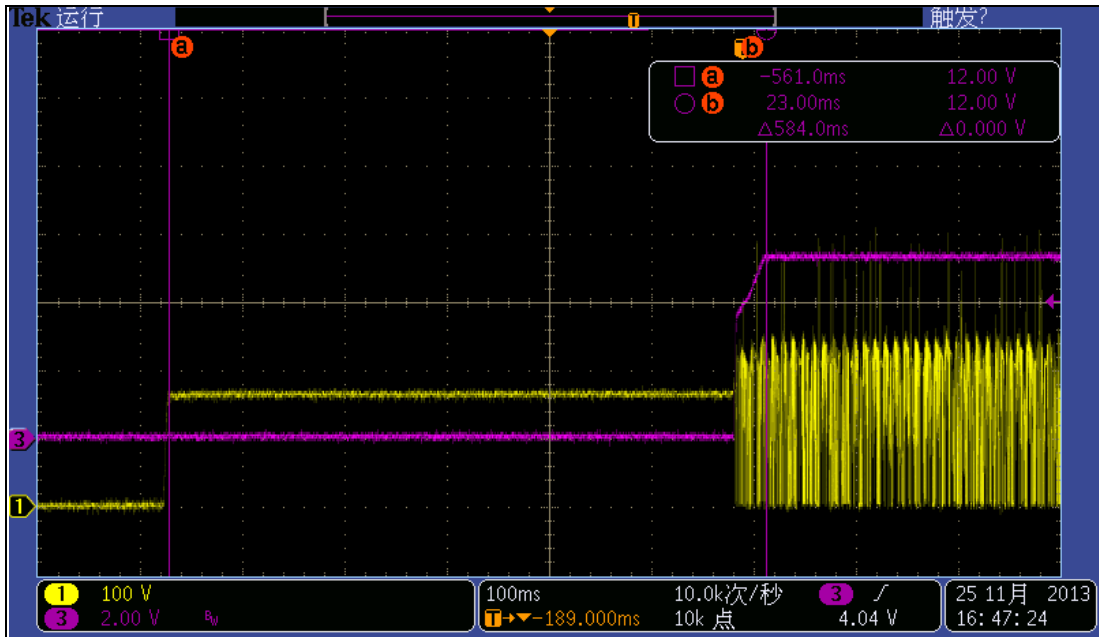


Vin:264Vac Io: 3A
 Ch1: Input bulk CAP voltage 100V/div
 Ch4: Input inrush current 1A/div

3 OUTPUT CHARACTERISTICS

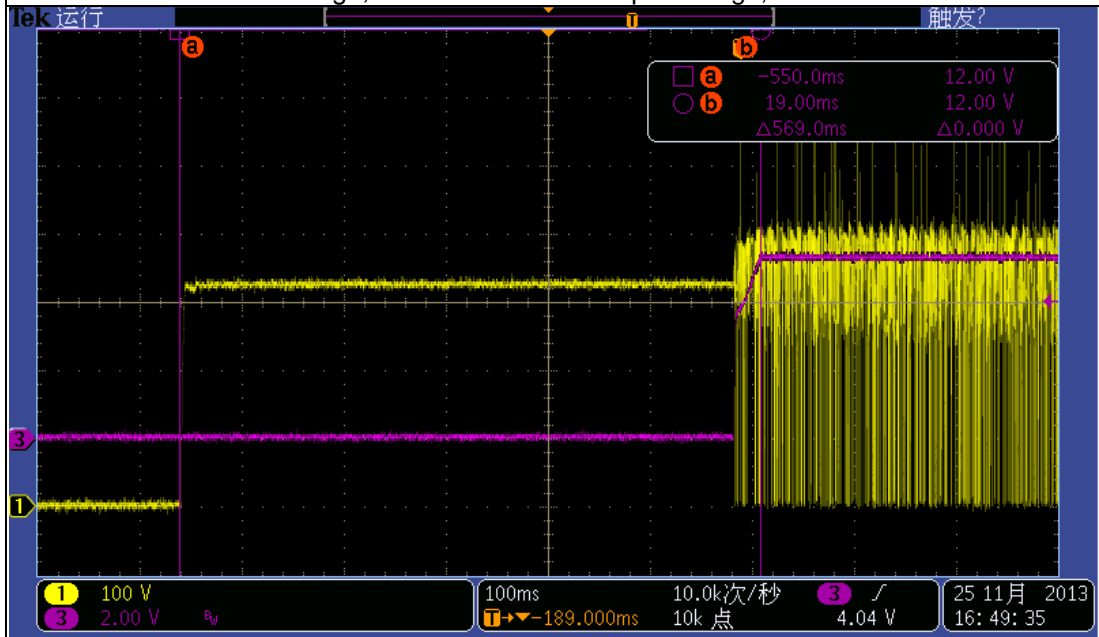
3.1 STARTUP TIME

Input voltage	Output current	Startup time	Pass/Fail
115Vac	3A	584mS	
230Vac	3A	569mS	



Vin:115Vac Io: 3A

Ch1: MOSFET's drain voltage, 100V/div Ch3: output voltage, 2V/div

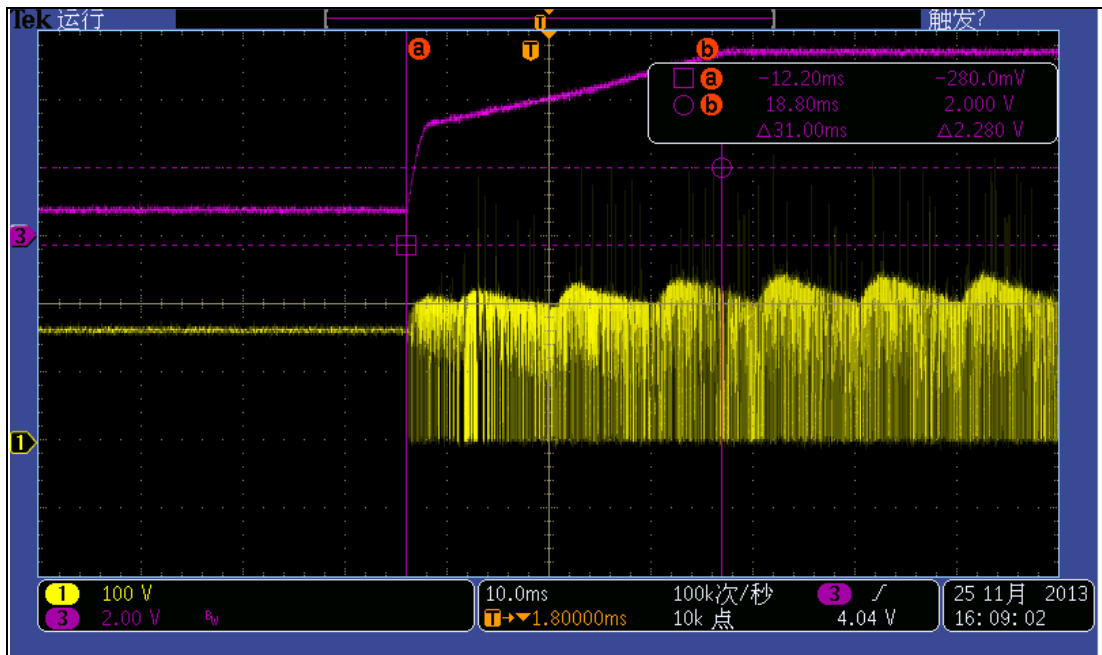


Vin:230Vac Io: 3A

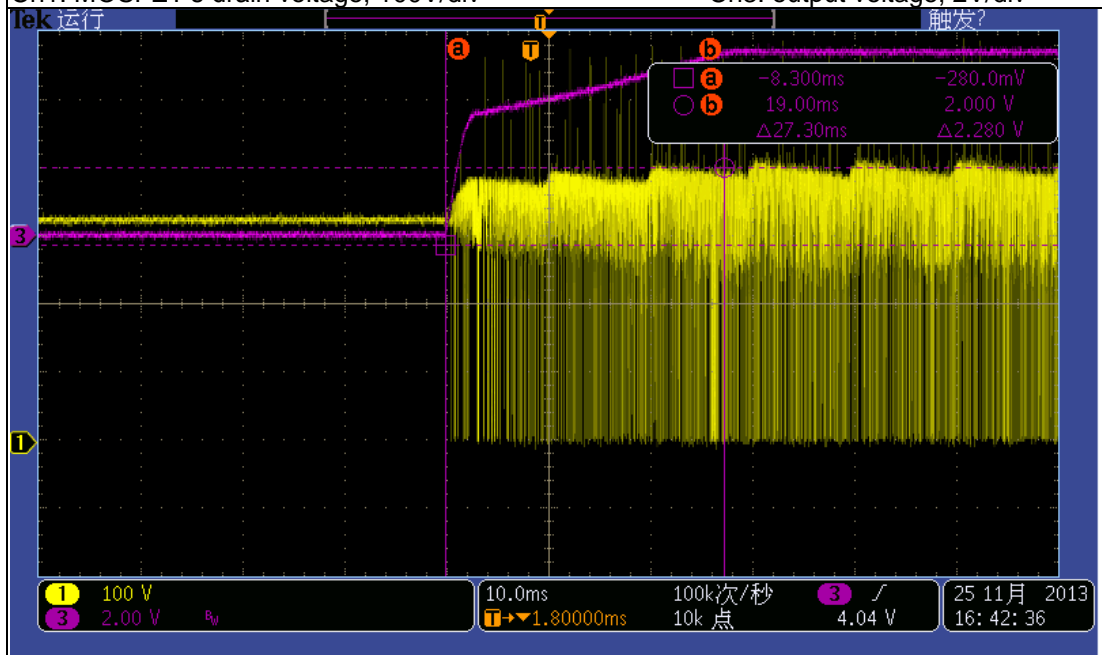
Ch1: MOSFET's drain voltage, 100V/div Ch3: output voltage, 2V/div

3.2 OUTPUT VOLTAGE RISE TIME

Input voltage	Output current	Startup time	Pass/Fail
115Vac	3A	31mS	
230Vac	3A	27.3mS	



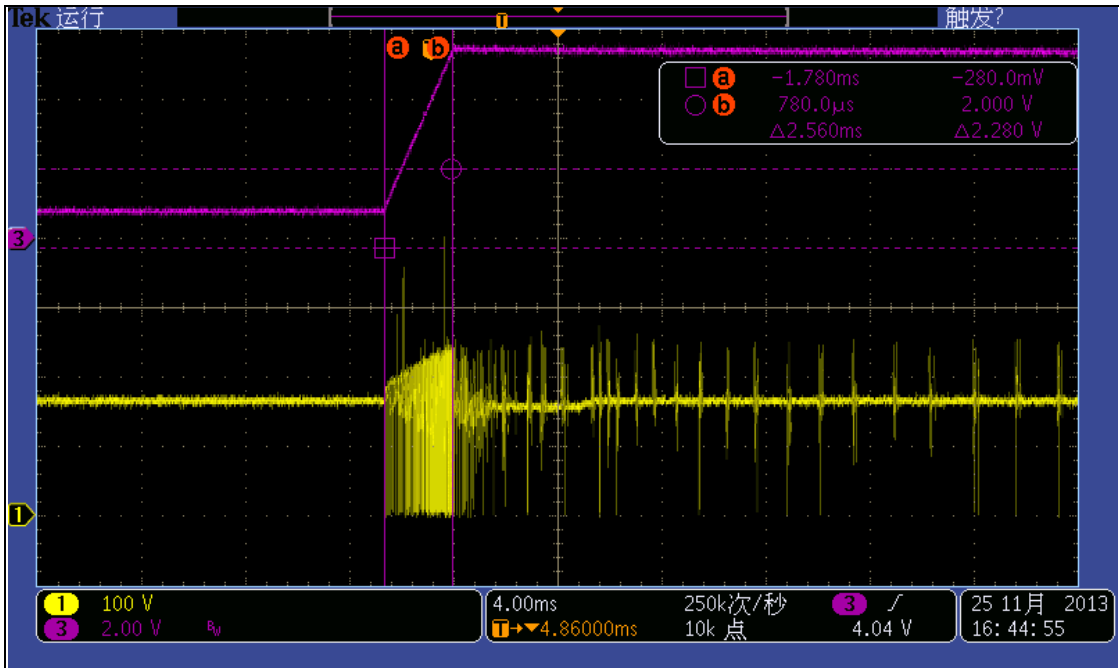
Vin:115Vac Io: 3A
Ch1: MOSFET's drain voltage, 100V/div Ch3: output voltage, 2V/div



Vin:230Vac Io: 3A
Ch1: MOSFET's drain voltage, 100V/div Ch3: output voltage, 2V/div

3.3 OUTPUT VOLTAGE OVERSHOOT

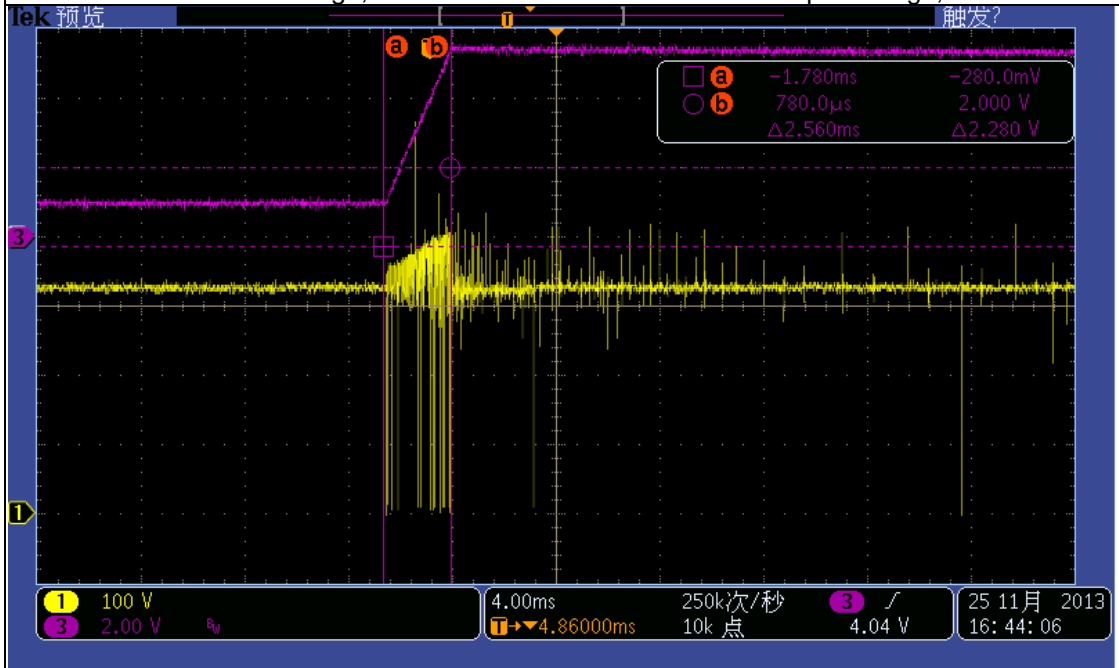
Input voltage	Output current	overshoot voltage	Pass/Fail
115Vac	0A	<1%	
230Vac	0A	<1%	



Vin:115Vac Io: 0A

Ch1: MOSFET's drain voltage, 100V/div

Ch3: output voltage, 2V/div



Vin:230Vac Io: 0A

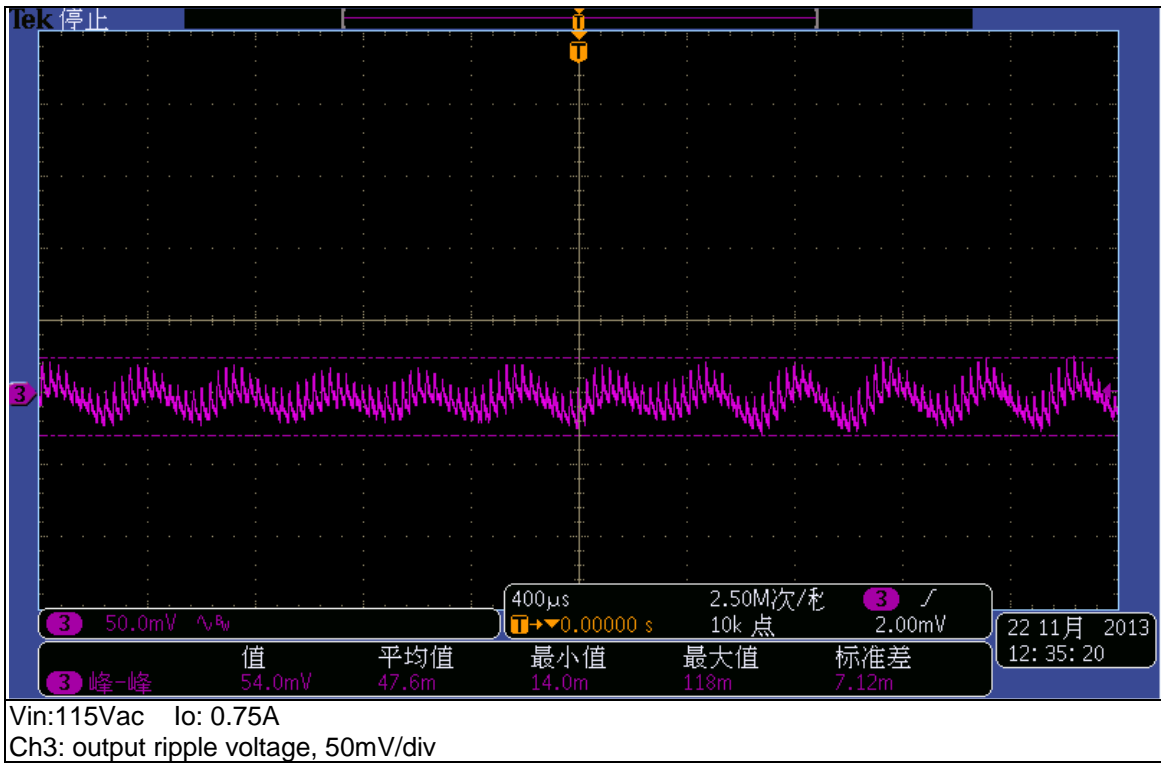
Ch1: MOSFET's drain voltage, 100V/div

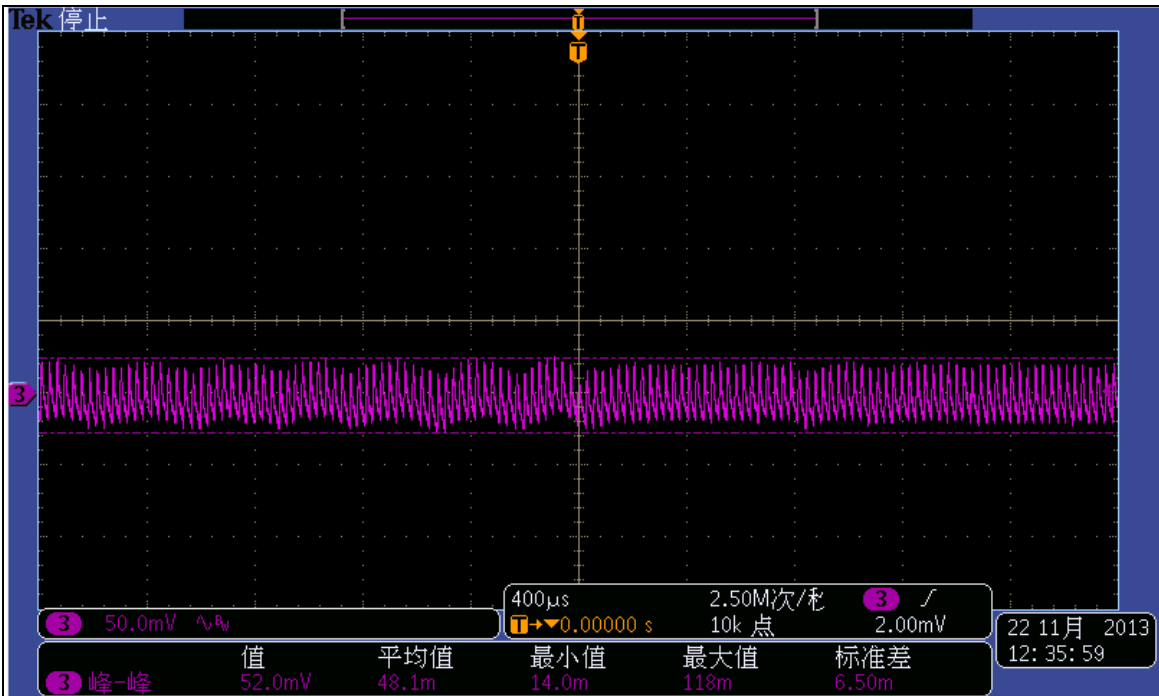
Ch3: output voltage, 2V/div

3.4 RIPPLE VOLTAGE

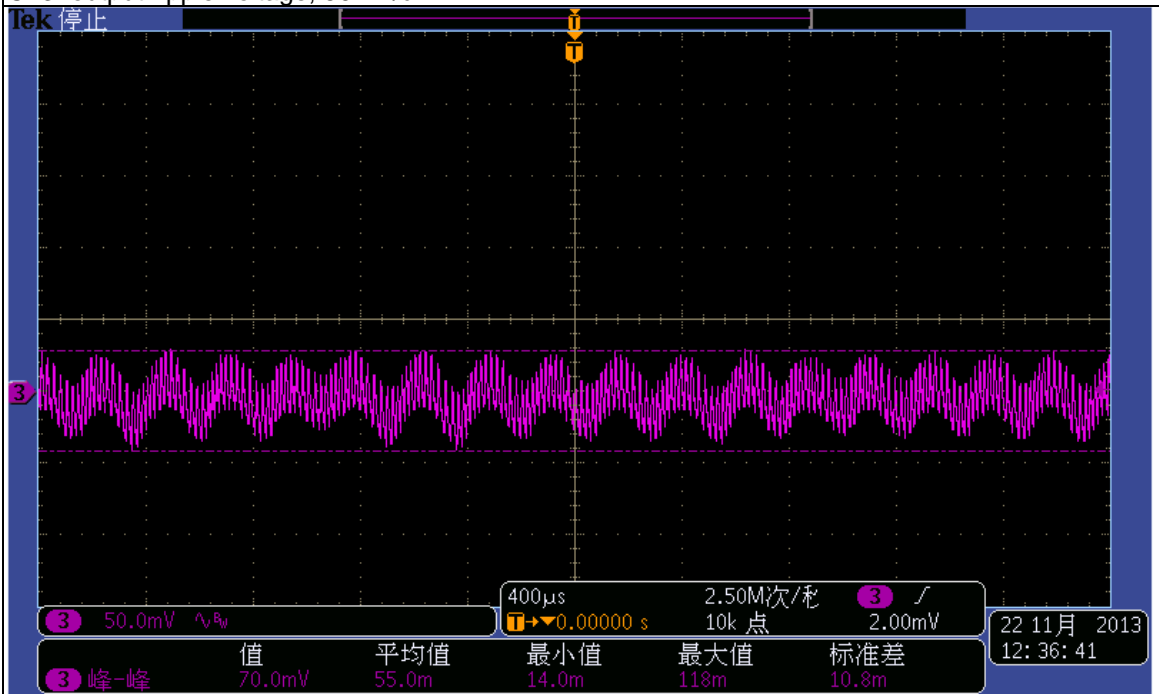
Input voltage	Output current	Ripple voltage	Pass/Fail
115Vac	0.75A	54mV	
115Vac	1.5A	52mV	

115Vac	2.25A	70mV	
115Vac	3A	62mV	
230Vac	0.75A	36mV	
230Vac	1.5A	58mV	
230Vac	2.25A	58mV	
230Vac	3A	66mV	

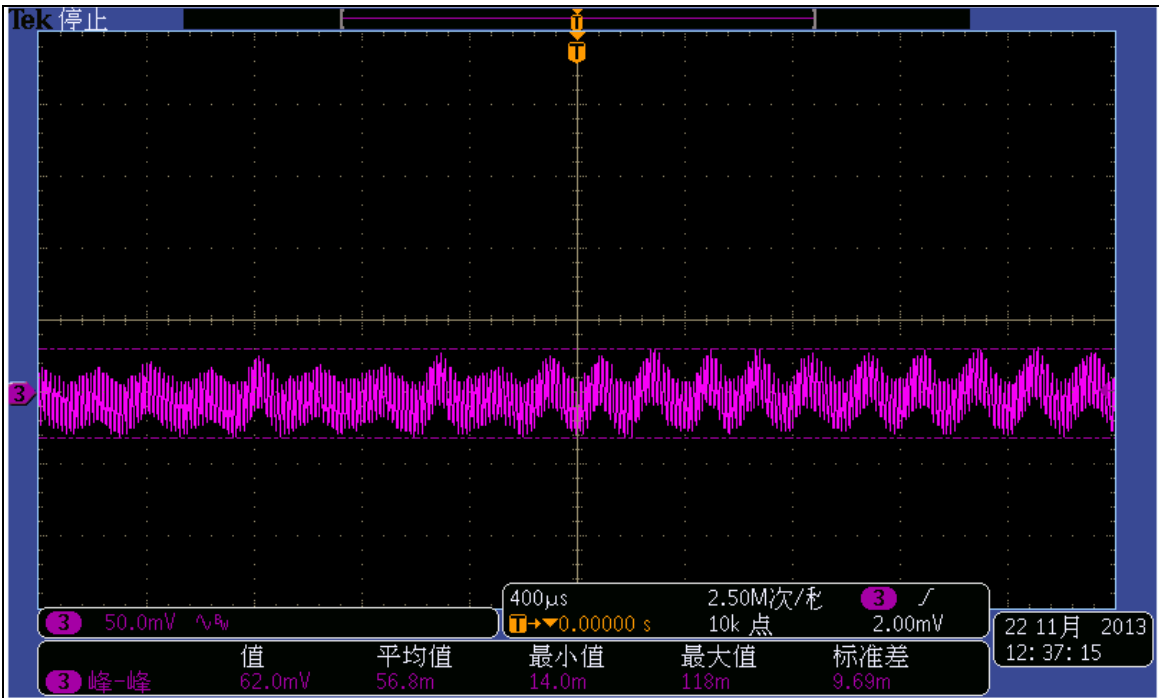




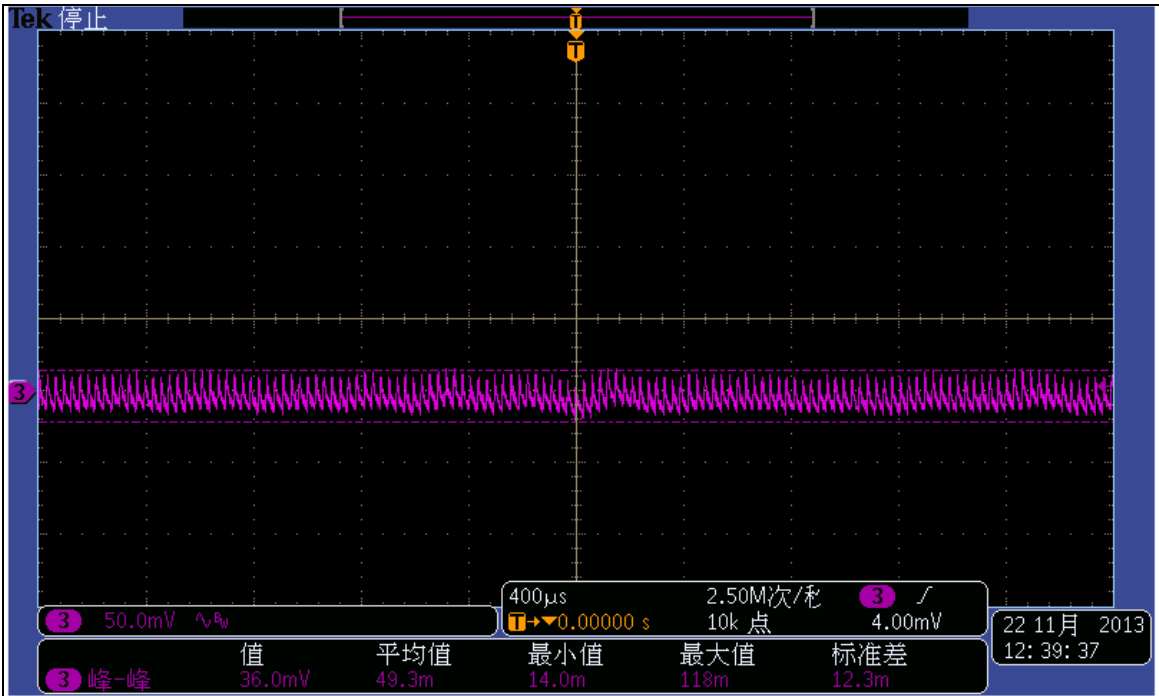
Vin:115Vac Io: 1.5A
Ch3: output ripple voltage, 50mV/div



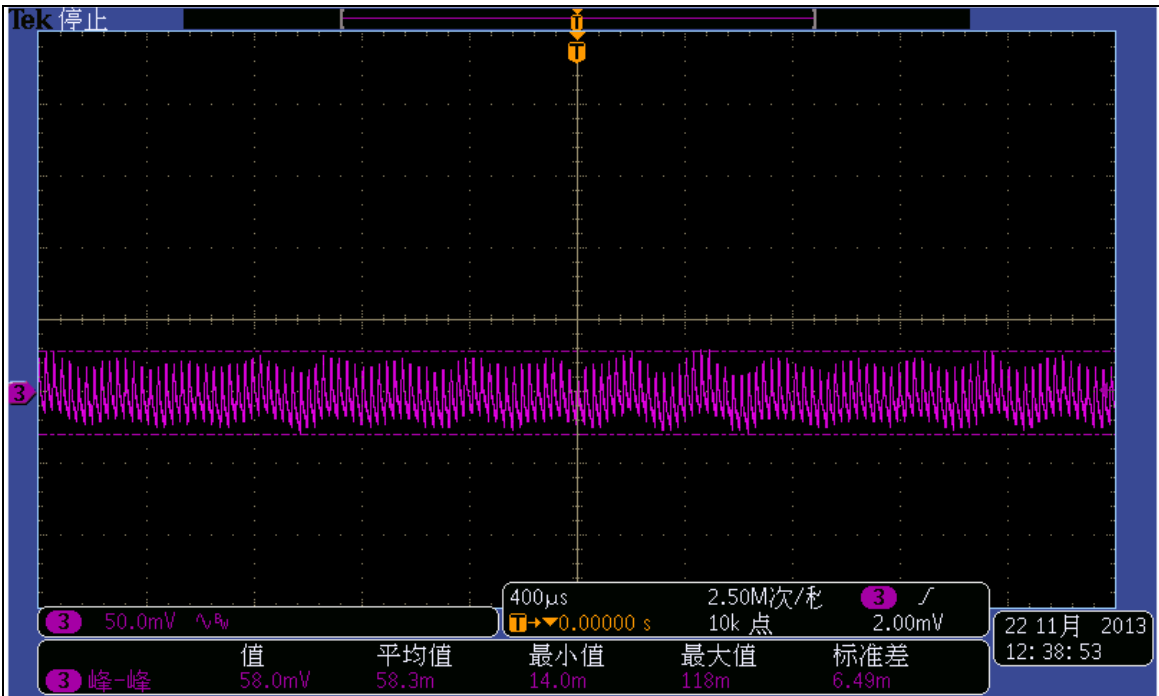
Vin:115Vac Io: 2.25A
Ch3: output ripple voltage, 50mV/div



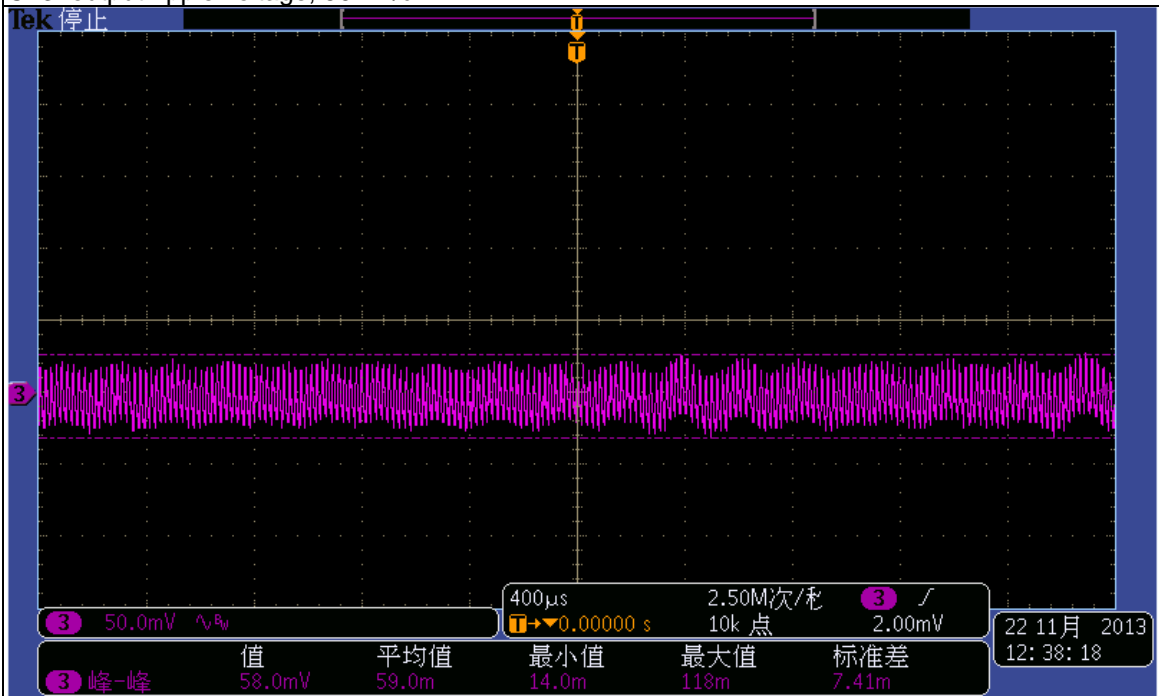
Vin:115Vac Io: 3A
Ch3: output ripple voltage, 50mV/div



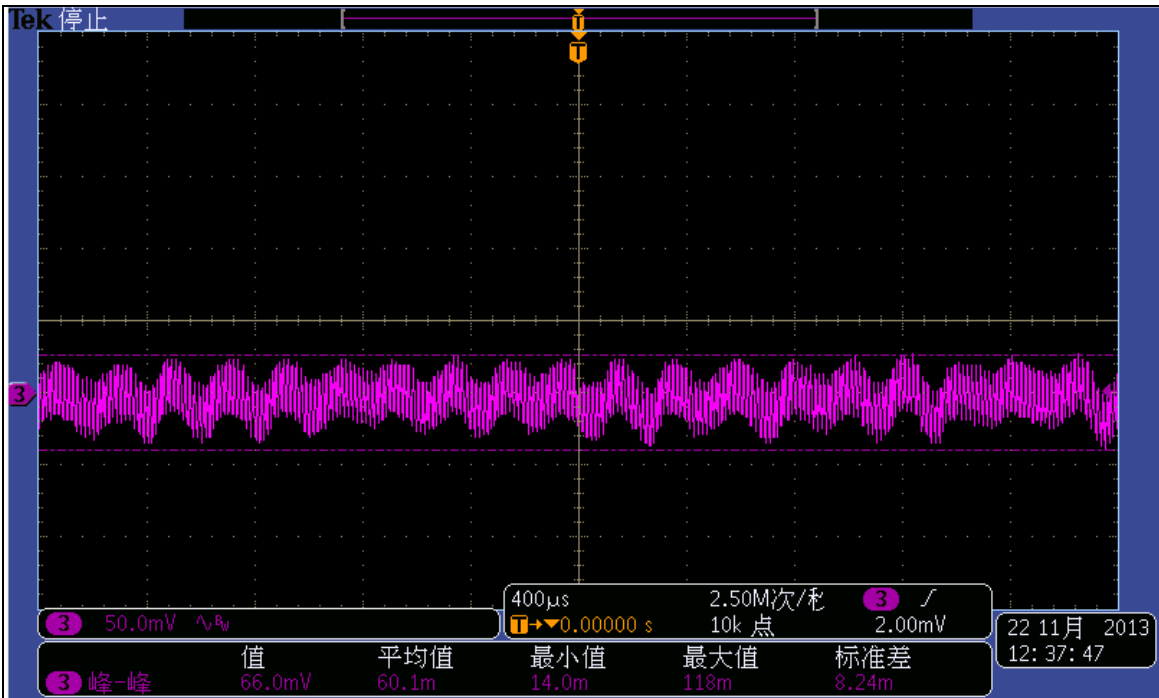
Vin:230Vac Io: 0.75A
Ch3: output ripple voltage, 50mV/div



Vin:230Vac Io: 1.5A
 Ch3: output ripple voltage, 50mV/div



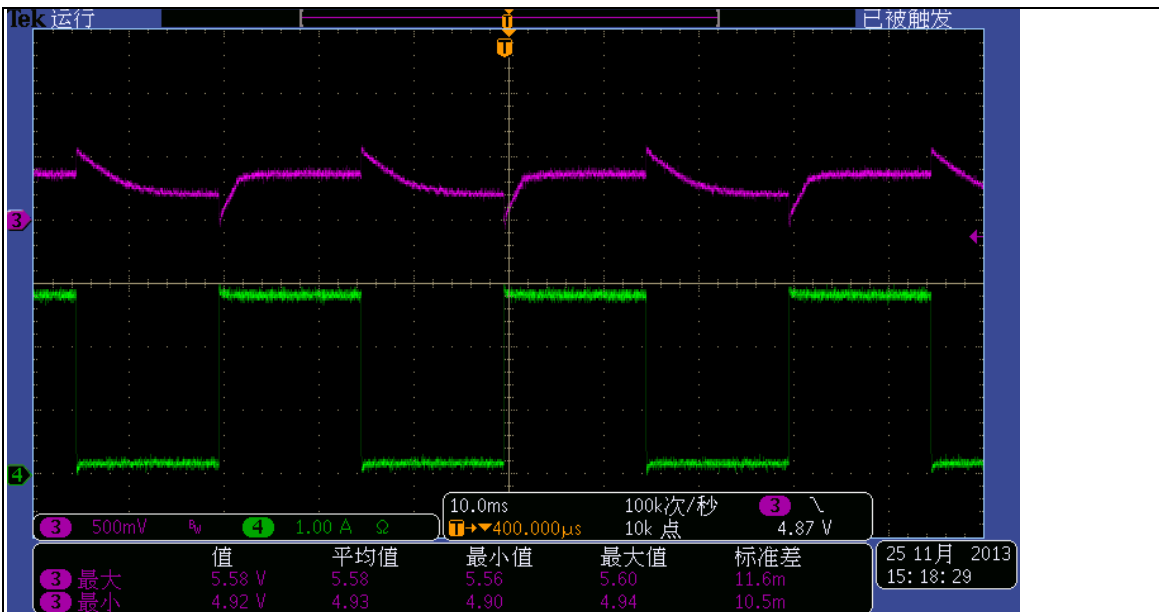
Vin:230Vac Io: 2.25A
 Ch3: output ripple voltage, 50mV/div



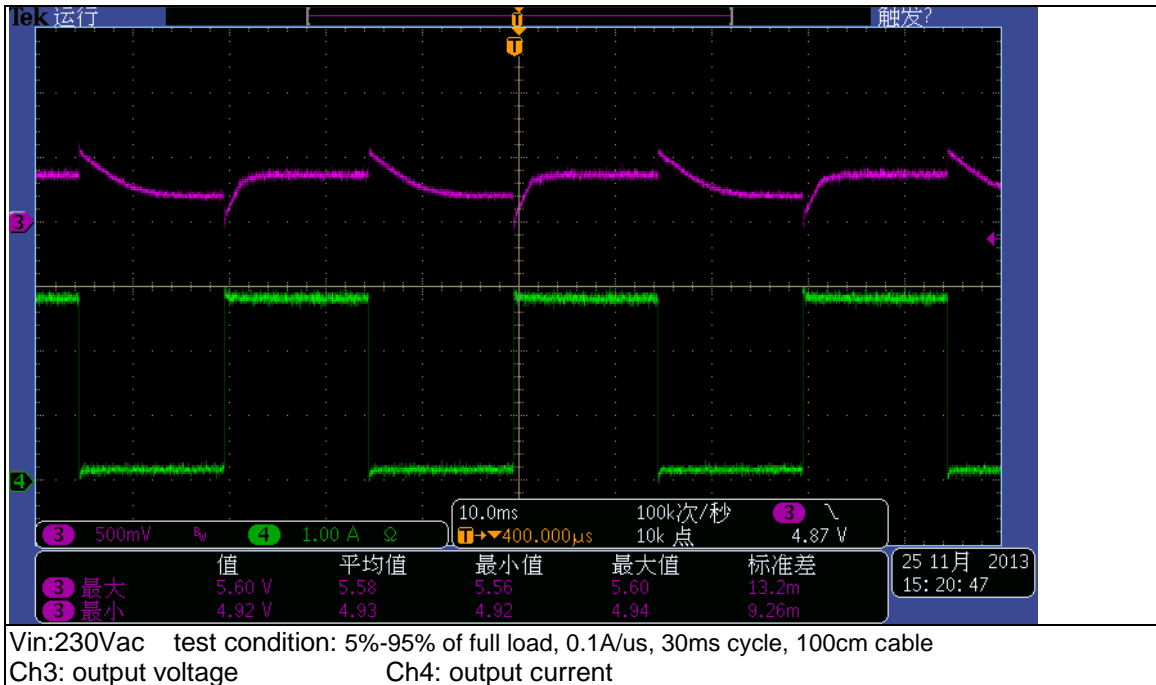
Vin:230Vac Io: 3A
Ch3: output ripple voltage, 50mV/div

3.5 DYNAMIC RESPONSE

Input voltage	Output current	Max voltage	Min voltage
115Vac	5%-95% of full load	5.58V	4.92V
230Vac	5%-95% of full load	5.6V	4.92V



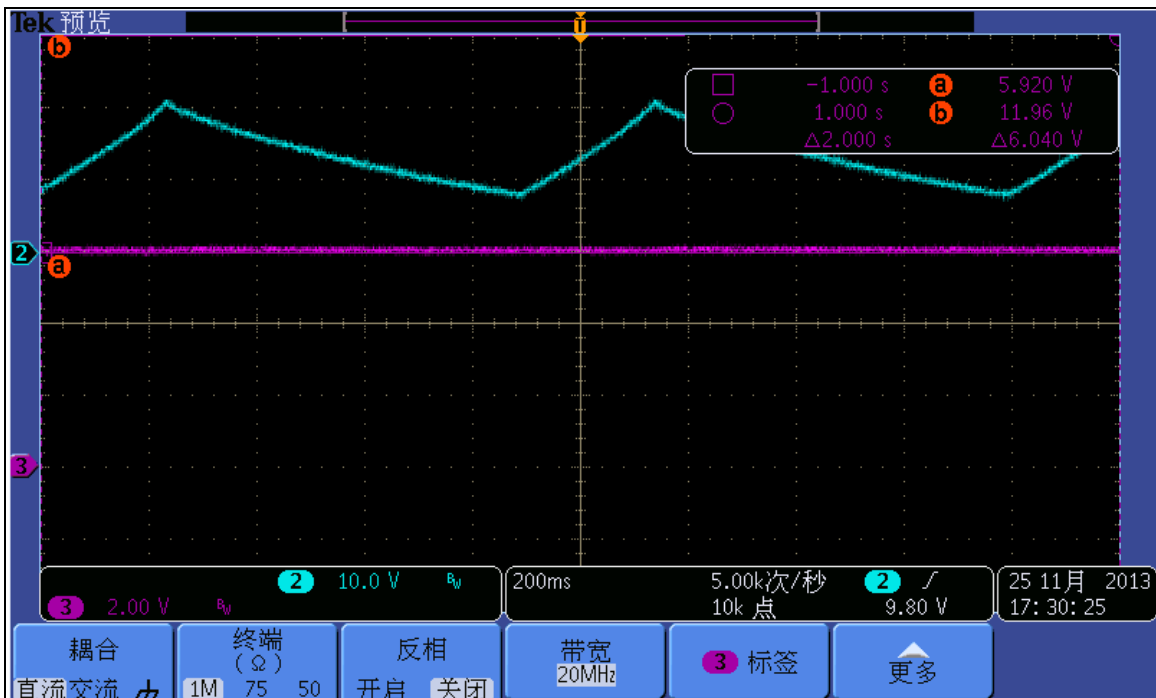
Vin:115Vac test condition: 5%-95% of full load, 0.1A/us, 30ms cycle, 100cm cable
Ch3: output voltage Ch4: output current



Vin:230Vac test condition: 5%-95% of full load, 0.1A/us, 30ms cycle, 100cm cable
 Ch3: output voltage Ch4: output current

3.6 OUTPUT VOLTAGE PROTECTION

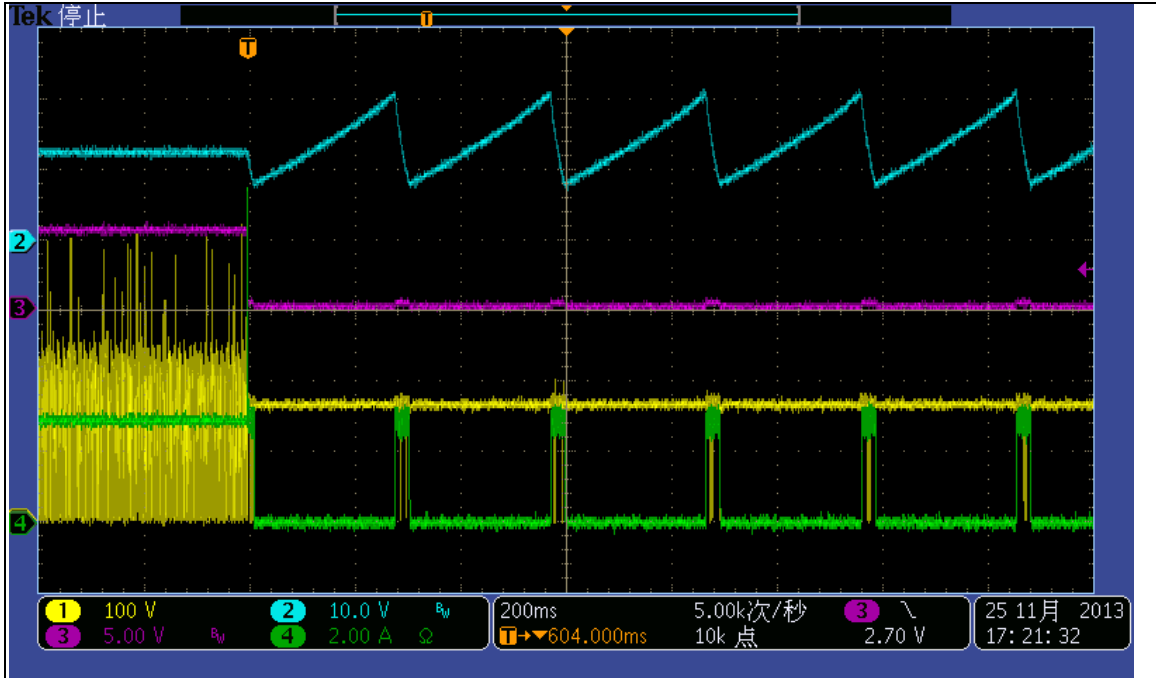
CONDITIONS	Protection voltage (V)	Pass/Fail
Vin (Vac)		
115&230	6	



Vin: 115Vac OVP: 6V
 CH2: Vdd voltage, 10V/div
 CH3: Vo, 2V/div

3.7 OUTPUT SHORT PROTECTION

Input voltage	Output short protection
115&230Vac	Hiccup up mode



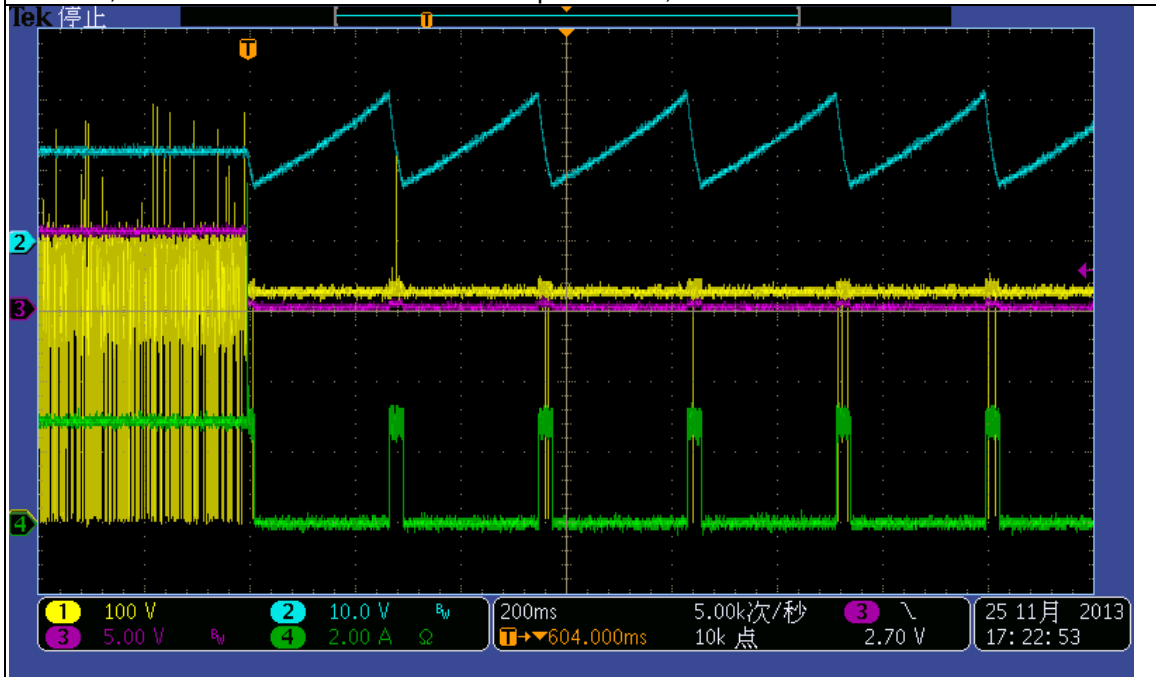
Vin:115Vac

CH1: Vds of MOSFET, 100V/div

CH2: Vdd, 10V/div

CH3: Vo, 5V/div

CH4: output current, 2A/div



Vin:230Vac

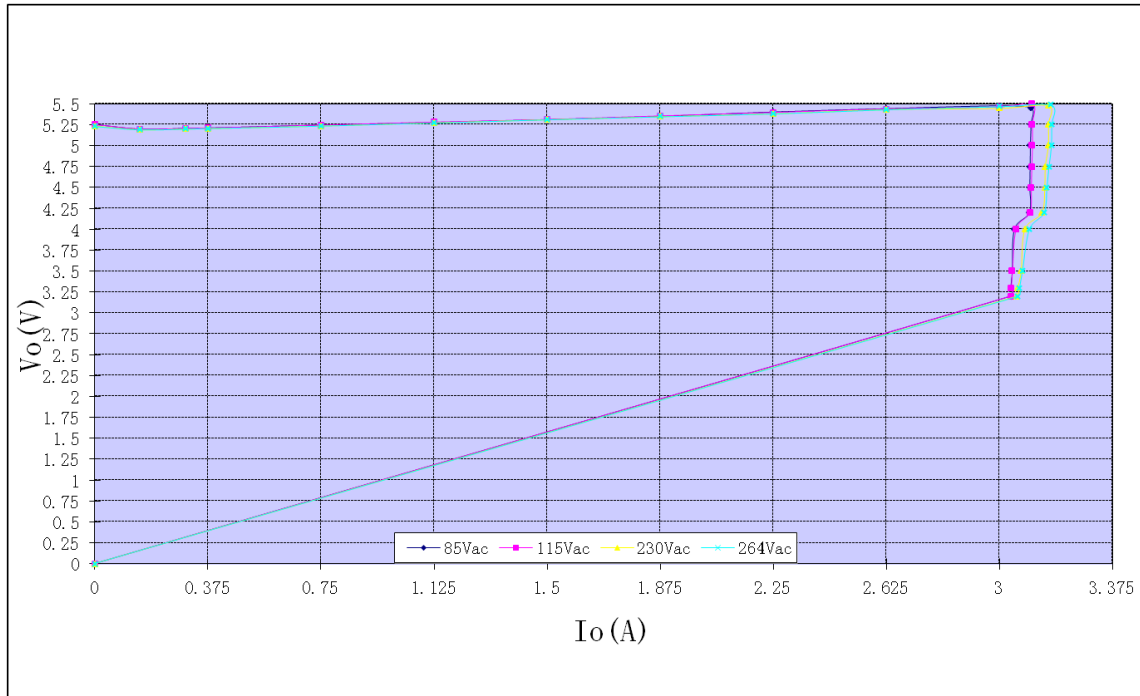
CH1: Vds of MOSFET, 100V/div

CH2: Vdd, 10V/div

CH3: Vo, 5V/div

CH4: output current, 2A/div

4 IV CURVE



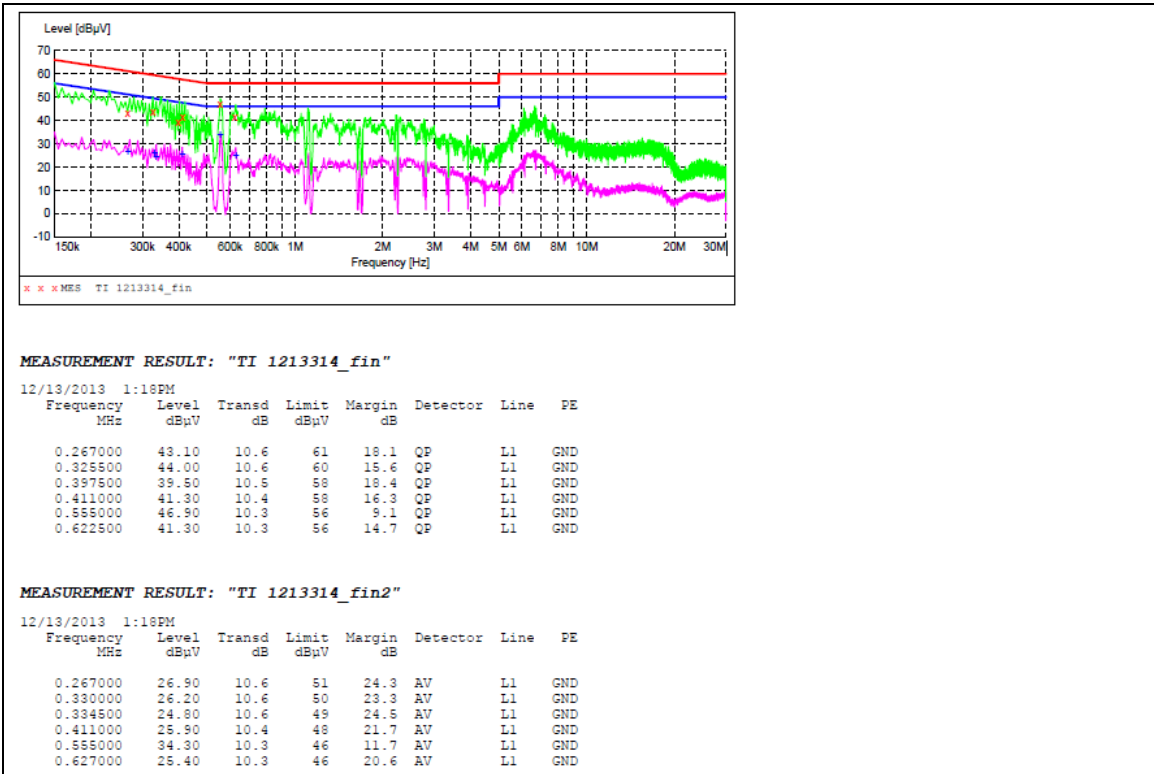
5 THERMAL TEST

5.1. Thermal test with case at $T_a=25^\circ\text{C}$

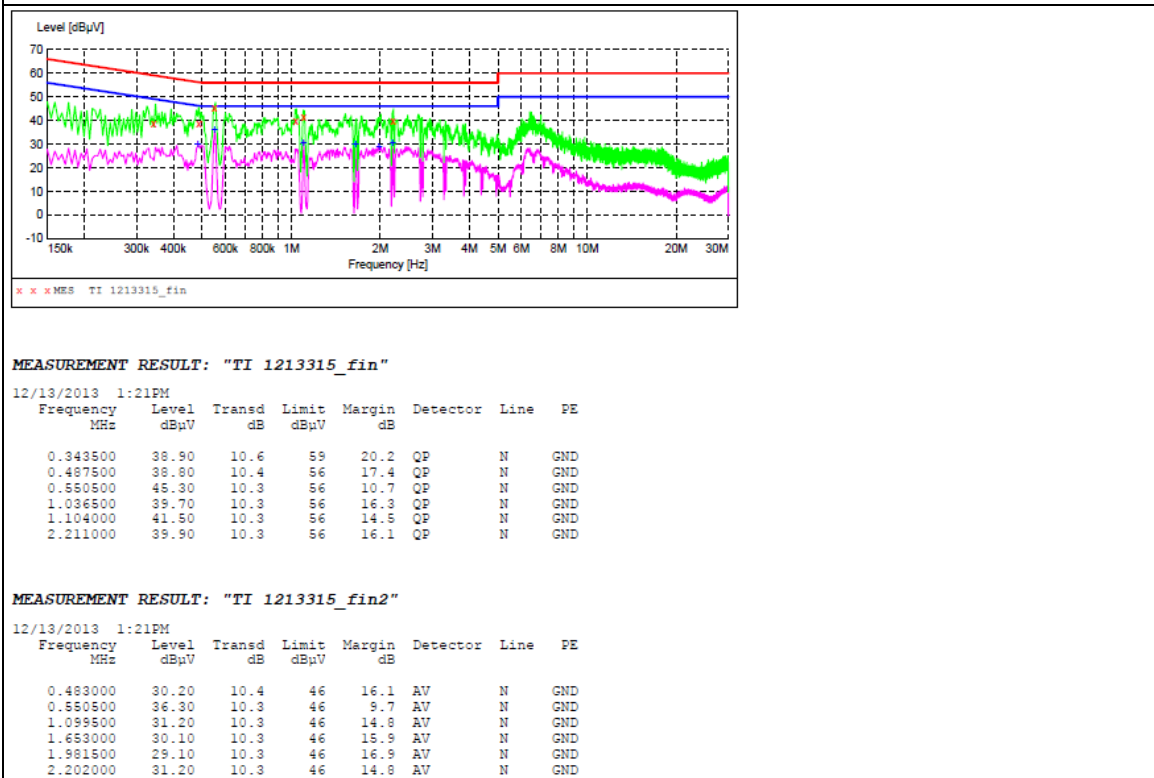
Temp record						
			90VAC 60Hz, Ambient:25 °C		264VAC 50Hz, Ambient:25 °C	
Thermal Coupler Channel	Name	Pos	test Time	CC	test Time	CC
			2 hrs	3A	2 hrs	3A
108	Input cap	C1	72° C		66.9° C	
101	Input cap	C2	74.7° C		69.5° C	
116	Schonounous MOSFET	Q1	66.6° C		69.7° C	
109	Transformer	T1 Core	75.1° C		75.6° C	
102	Transformer	T1 Winding	76.1° C		75.5° C	
111	Power Switch	Q2	71.1° C		81.6° C	
106	Output cap	C13	51.7° C		51.3° C	
114	Output cap	C14	48.6° C		48.8° C	
74	Output rectifier	D7	74° C		73.5° C	
113	Rect. bridge diode	D1	83.9° C		78° C	
115	UCC28713	U2	72.8° C		74.6° C	
117	UCC24610	U1	65.2° C		67.9° C	
107	Top of shell	TP1	50.4° C		51.5° C	
104	Front of shell	TP2	48.7° C		45.3° C	
110	Rear of shell	TP3	41.2° C		33.2° C	
105	Side of shell	TP4	52.5° C		53.2° C	

6 EMI Test

6.1 Conduction emission



Vin: 230Vac, Line, Io: 3A Test condition: 1.5m cable with 1.77R load resistor



Vin: 230Vac, Neutral, Io: 3A Test condition: 1.5m cable with 1.77R load resistor

6.2 Radiation emission

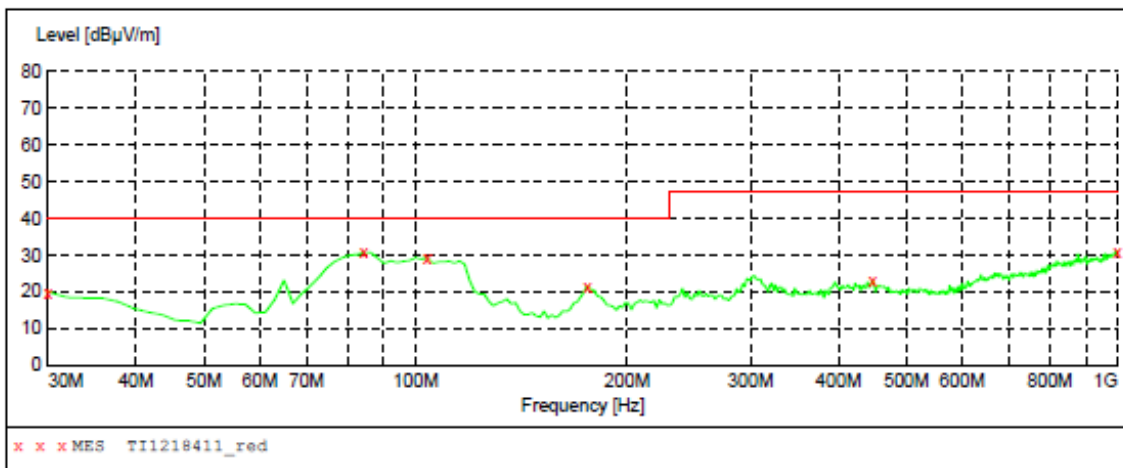
SHENZHEN HUATONGWEI INTERNATIONAL INSPECTION CO.,LTD

RADIATED EMISSION TEST EN 55022 CLASS B

EUT: PMP4390-3
 Manufacturer: TI
 Operating Condition: FULL LOAD
 Test Site: 3M CHAMBER
 Operator: MINGHUA.FAN
 Test Specification: AC 230V/50Hz
 Comment:
 Start of Test: 12/18/2013 / 9:36:28AM

SWEEP TABLE: "test (30M-1G)"

Short Description: Field Strength



MEASUREMENT RESULT: "TI1218411_red"

12/18/2013 9:38AM

Frequency MHz	Level dBµV/m	Transd dB	Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
30.000000	19.90	-10.0	40.0	20.1	---	100.0	155.00	HORIZONTAL
84.428858	30.70	-19.7	40.0	9.3	---	300.0	192.00	HORIZONTAL
103.867735	29.30	-18.3	40.0	10.7	---	300.0	26.00	HORIZONTAL
175.791583	21.60	-21.0	40.0	18.4	---	300.0	329.00	HORIZONTAL
447.935872	23.10	-12.7	47.0	23.9	---	100.0	184.00	HORIZONTAL
1000.000000	31.00	-2.9	47.0	16.0	---	100.0	279.00	HORIZONTAL

Vin: 230Vac, Horizontal, Io: 3A

Test condition: 1.5m cable with 1.77R load resistor

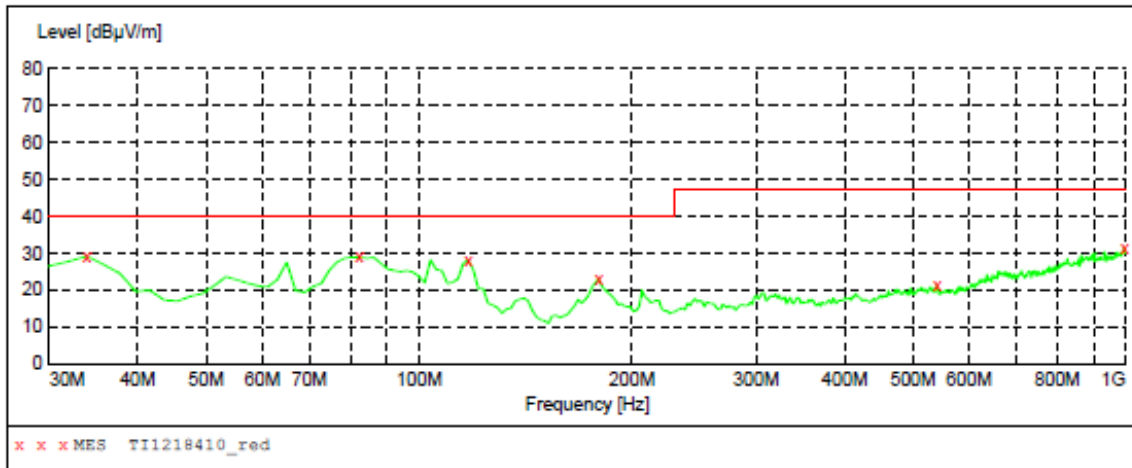
SHENZHEN HUATONGWEI INTERNATIONAL INSPECTION CO.,LTD

RADIATED EMISSION TEST EN 55022 CLASS B

EUT: PMP4390-3
Manufacturer: TI
Operating Condition: FULL LOAD
Test Site: 3M CHAMBER
Operator: MINGHUA.FAN
Test Specification: AC 230V/50Hz
Comment:
Start of Test: 12/18/2013 / 9:34:40AM

SWEEP TABLE: "test (30M-1G)"

Short Description: Field Strength



MEASUREMENT RESULT: "TI1218410_red"

12/18/2013 9:36AM

Frequency MHz	Level dBµV/m	Transd dB	Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarisation
33.887776	29.20	-12.0	40.0	10.8	---	100.0	90.00	VERTICAL
82.484970	28.90	-19.9	40.0	11.1	---	100.0	149.00	VERTICAL
117.474950	28.20	-18.0	40.0	11.8	---	100.0	107.00	VERTICAL
179.679359	23.00	-20.5	40.0	17.0	---	100.0	287.00	VERTICAL
541.242485	21.20	-11.6	47.0	25.8	---	100.0	299.00	VERTICAL
996.112224	31.40	-3.0	47.0	15.6	---	100.0	310.00	VERTICAL

Vin:230Vac, Vertical, Io: 3A Test condition: 1.5m cable with 1.77R load resistor

IMPORTANT NOTICE FOR TI REFERENCE DESIGNS

Texas Instruments Incorporated ("TI") reference designs are solely intended to assist designers ("Buyers") who are developing systems that incorporate TI semiconductor products (also referred to herein as "components"). Buyer understands and agrees that Buyer remains responsible for using its independent analysis, evaluation and judgment in designing Buyer's systems and products.

TI reference designs have been created using standard laboratory conditions and engineering practices. **TI has not conducted any testing other than that specifically described in the published documentation for a particular reference design.** TI may make corrections, enhancements, improvements and other changes to its reference designs.

Buyers are authorized to use TI reference designs with the TI component(s) identified in each particular reference design and to modify the reference design in the development of their end products. HOWEVER, NO OTHER LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE TO ANY OTHER TI INTELLECTUAL PROPERTY RIGHT, AND NO LICENSE TO ANY THIRD PARTY TECHNOLOGY OR INTELLECTUAL PROPERTY RIGHT, IS GRANTED HEREIN, including but not limited to any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services, or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

TI REFERENCE DESIGNS ARE PROVIDED "AS IS". TI MAKES NO WARRANTIES OR REPRESENTATIONS WITH REGARD TO THE REFERENCE DESIGNS OR USE OF THE REFERENCE DESIGNS, EXPRESS, IMPLIED OR STATUTORY, INCLUDING ACCURACY OR COMPLETENESS. TI DISCLAIMS ANY WARRANTY OF TITLE AND ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, QUIET ENJOYMENT, QUIET POSSESSION, AND NON-INFRINGEMENT OF ANY THIRD PARTY INTELLECTUAL PROPERTY RIGHTS WITH REGARD TO TI REFERENCE DESIGNS OR USE THEREOF. TI SHALL NOT BE LIABLE FOR AND SHALL NOT DEFEND OR INDEMNIFY BUYERS AGAINST ANY THIRD PARTY INFRINGEMENT CLAIM THAT RELATES TO OR IS BASED ON A COMBINATION OF COMPONENTS PROVIDED IN A TI REFERENCE DESIGN. IN NO EVENT SHALL TI BE LIABLE FOR ANY ACTUAL, SPECIAL, INCIDENTAL, CONSEQUENTIAL OR INDIRECT DAMAGES, HOWEVER CAUSED, ON ANY THEORY OF LIABILITY AND WHETHER OR NOT TI HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES, ARISING IN ANY WAY OUT OF TI REFERENCE DESIGNS OR BUYER'S USE OF TI REFERENCE DESIGNS.

TI reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques for TI components are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

Reproduction of significant portions of TI information in TI data books, data sheets or reference designs is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards that anticipate dangerous failures, monitor failures and their consequences, lessen the likelihood of dangerous failures and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in Buyer's safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed an agreement specifically governing such use.

Only those TI components that TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components that have **not** been so designated is solely at Buyer's risk, and Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.